Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/656,668	CHEN, BOMY
Examiner	Art Unit
Long Pham	2814

	SEARCHED				
Class	Subclass	Date	Examiner		
438	95,98 102	2/2/2005	LP		
257	2, 4,5,	2/2/2005	LP		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
257	02	2/2/2005	LP	
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SEAR (INCLUDING S	CH NOTES EARCH STRATEGY	()
	DATE	EXMR
text searches	2/2/2005	LP
		